

AP 20 Rec'd PCT TO 20 MAR 2006

<b>APPLICANT'S ART CITATION</b> (Use several sheets if necessary)	Application <b>AP 20 Rec'd PCT TO 20 MAR 2006</b> OFGS File No. <b>130-573605</b>
	Applicant <b>Johannes WEIERMAIR et al.</b>
	Filing Date <b>4/26/2006</b> Group Art Unit <b>3725</b>

**U.S. PATENT DOCUMENTS** (not submitted for applications filed after 6/30/03)

Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
/DS/	US-4,392,759	07-1983	Cook	403	11	
↓	US-3,926,532	12-1975	Schlenker et al.	403	322	
↓	US-2,697,335	12-1954	Peterson	64	8	
/DS/	US-5,000,024	03-1991	Seidl et al.	72	249	
	US-					
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	US-					

**FOREIGN PATENT DOCUMENTS**

	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
/DS/	DE 101 58 711 A1	06-2003	Germany			abstract	
↓	EP 0 728 538 A1	08-1996	Europe			abstract	
↓	DE 4035941	05-1992	Germany			abstract	
↓	DE 195 08 526	09-1996	Germany			abstract	
/DS/	GB 2 288 003 A	10-1995	United Kingdom			X	

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

/DS/	International Search Report PCT/EP2004/009679 dated 19 November 2004

Examiner <b>/Dmitry Suhol/ (10/13/2007)</b>	Date Considered <b>10/13/2007</b>
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